## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
09925397	CHANG ET AL.
Examiner	Art Unit
Ehichioya, Fred I	2162

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES			
Search Notes	Date	Examiner	
IEEE Xplore	12/16/07	FE	
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	12/17/07	FE	
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	6/24/08	FE	
Google.com	6/24/08	FE	
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	2/23/2009	FE	
Google Search	2/20/2009	FE	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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